

WEST

Freeform Search

Database:

US Patents Full-Text Database
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JPO Abstracts Database
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Derwent World Patents Index
IBM Technical Disclosure Bulletins

Term:

11 and (test\$3 or debug\$4 or verif\$7 or diagno\$5
or probing or probe or exerci\$4) same (ic or
(integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or
memor\$7) same (compress\$5 or de\$1compress\$4 or

Display: **Documents in Display Format:** **Starting with Number** **Generate:** ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image

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DATE: Monday, September 09, 2002 [Printable Copy](#) [Create Case](#)

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	<i>DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>		
<u>L10</u>	('5991232')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L10</u>
<u>L9</u>	('6163491')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L9</u>
<u>L8</u>	('20010014922' '20020099987')[ABPN1,NRPN,PN,TBAN,WKU]	3	<u>L8</u>
<u>L7</u>	l6 and (DDR or (Double Data Rate)) same (rising or leading or trailing or falling) near2 (edge or clock\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) same (compres\$5 or de\$1compres\$4 or compac\$6)	2	<u>L7</u>
<u>L6</u>	(DDR or (Double Data Rate)) same (rising or leading or trailing or falling) near2 (edge or clock\$4)	313	<u>L6</u>
<u>L5</u>	('20010014922')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L5</u>
<u>L4</u>	l3 and (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) same (compres\$5 or de\$1compres\$4 or compac\$6) same clock\$4 and double near2 rate and transistor same (pull\$1up or pull\$1down)	1	<u>L4</u>
<u>L3</u>	l1 and (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) same (compres\$5 or de\$1compres\$4 or compac\$6) same clock\$4 and double near2 rate	6	<u>L3</u>
<u>L2</u>	l1 and (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) same (compres\$5 or de\$1compres\$4 or compac\$6) same clock\$4 same double near2 rate	0	<u>L2</u>
<u>L1</u>	(test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) same (compres\$5 or de\$1compres\$4 or compac\$6) same clock\$4	272	<u>L1</u>

END OF SEARCH HISTORY